



# **Tessent™ TestKompress® and Advanced Topics Student Workbook**

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**Contractor/manufacturer is:**

Mentor Graphics Corporation  
8005 S.W. Boeckman Road, Wilsonville, Oregon 97070-7777.  
Telephone: 503.685.7000  
Toll-Free Telephone: 800.592.2210  
Website: [www.mentor.com](http://www.mentor.com)  
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